

Clean Copy of Claims

The following is a clean copy of amended claims 1 and 8.

1 1. An integrated circuit including an embedded memory and a built-in self-test arrangement

2 including

3 means for storing test instruction including means for discriminating a source of a test

4 command for performing manufacturing level and board level testing and receiving test

5 instructions provided from an external tester,

6 means for generating default test instructions, and

7 means for supplying said default test instructions to said means for storing test

8 instructions.

1 8. An electronic system including an integrated circuit having a built-in self-test arrangement

2 therein, said integrated circuit including

3 means for storing test instructions including means for discriminating a source of a test

4 command for performing manufacturing level and board level testing and receiving test

5 instructions provided from an external tester,

6 means for generating default test instructions in absence of instructions from an external

7 tester, and

8 means for supplying said default test instructions to said means for storing test

9 instructions.